Unveiling layer-dependent interlayer coupling and vibrational properties in MoTe₂ under high pressure

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Layered materials have garnered significant attention for their ability to exhibit tunable physical properties through stacking, twisted angles, and interlayer coupling. The interlayer vibrations in these materials are highly sensitive to, and can be controlled by, their thickness. However, the layer-dependent interlayer vibration behavior under high pressure remains unclear. Here, we investigate the layer-dependent high-pressure Raman spectroscopy of 1–5L and bulk MoTe₂ up to 14-GPa pressure, and demonstrate a pressure-induced thickness-dependent interlayer vibration behavior. We observe the pressure-induced blueshift rates of the breathing (LB) and shear (S) modes exhibit opposite strong layer-dependent behaviors, which arise from thickness-dependent interlayer coupling and restoring forces, respectively. Furthermore, we propose a pressure-dependent linear chain model to characterize the force constants under pressure and employ a bond-polarization model to explain the intensity changeover between the S and LB modes, as well as between the A_1'/A_{1g}^2 and E'/E_g^1 modes, which is attributed to the increase in interlayer Te–Te bond angle and intralayer distance between Mo and Te atomic layers, respectively. Our findings elucidate the robust thickness-dependent interlayer vibrations in MoTe₂ and provide a firm foundation for exploring and characterizing interlayer coupling through pressure engineering in van der Waals materials.

I. INTRODUCTION

Layered materials, such as graphene [1], black phosphorus [2], and transition-metal chalcogenides (TMDs) [3], exhibit a unique crystal structure characterized by van der Waals interactions between layers. This distinctive structure imparts them with remarkable properties, including high carrier mobility [4], extraordinary optoelectronic properties [5,6] and layer-dependent band gaps [7,8], making them highly valuable in various applications such as optoelectronic detector [9], spintronic [10], valley optoelectronics [11], and field-effect transistors [12]. In particular, such structural features enable flexible tuning of their properties through methods such as stacking [13], twisted angle [14–17], and the application of external field [18–20]. Current research

efforts have extensively explored structural transition [21,22], semiconductor-to-metal transition [23,24], optical transition changeover [25,26], and pressure-induced superconductor [27,28] in layered materials and their heterostructures, accomplished by adjusting the interlayer coupling through high pressure. The high-pressure studies for two-dimensional (2D) materials have been focused on their monolayer [29], bilayers [30], heterostructures [31], and bulk [32]. However, there is a lack of systematic high-pressure studies on 2D materials with varying layer numbers. In TMDs, the low-frequency interlayer vibration modes are highly sensitive to the number of layers [33–35], resulting in blue- and redshifts for shear (S) and breathing (LB) modes, respectively, as the thickness increases. The description of these low-frequency S and LB modes can be achieved using the linear chain model (LCM) [36,37], and their layer-dependent behavior can be characterized by a fan diagram [33]. Given that the S and LB modes are closely related to interlayer interactions, pressure can effectively modulate these modes by controlling the interlayer coupling. However, the response of S and LB modes in 2D

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materials with different thicknesses under pressure remains poorly understood.

In this work, we performed high-pressure Raman spectroscopy studies on monolayer (1L) to pentalayer (5L) and bulk MoTe$_2$ using diamond-anvil cell (DAC) devices. The obtained high-pressure Raman spectra revealed that the blueshift ratio of the S and LB modes is dependent on the layer number, exhibiting contrasting trends due to the layer-dependent restoring force and interlayer coupling, respectively. Moreover, we extended the LCM to the pressure field and obtained a continuous increase in the force constants of the S and LB modes with increasing pressure. Additionally, we uncovered a pressure-induced intensity changeover between the S and LB modes, as well as between A_1'/A_{1g}^2 and E'/E_g^1 modes. By employing the bond-polarization model, we identified that this intensity changeover arises from pressure-induced alterations in the polarization component of the interlayer Te–Te or intralayer Mo–Te bonds. Our study provides insights into the layer-dependent atomic vibrations and their responses under high pressure.

II. METHODS

A. Sample preparation

The layer-dependent samples used in this study were prepared through gold-assisted mechanical exfoliation [38,39] from bulk MoTe$_2$ crystals grown by flux-zone growth (Flux) implemented by the 2D Semiconductors company. A layer of 130–140-nm-thick gold was deposited onto the bulk MoTe$_2$ samples by a vacuum thermal evaporation device. Subsequently, thermal release tape was employed to adhere these gold films, and then obtain the few-layer (1–5 L) samples using potassium iodide solution (KI:I$_2$:deionized water = 4 g:0.5 g:40 g) to etch the gold layer. In order to conduct high-pressure experiments, these samples were transferred from Si/SiO$_2$ substrates to the DAC culets using a dry-transfer method [40,41] with transfer medium of Polycarbonate (PC) glue. We dripped PC glue onto polydimethylsiloxane stuck on a glass slide, and then heated the Si/SiO$_2$ substrate to $80° - 90°$ C temperature. Upon cooling to room temperature, the MoTe$_2$ samples were picked up. Afterward, the samples attached to PC glue were heated to $90° - 100°$ C temperature, enabling the release of these samples with PC glue onto culets of DAC. The PC glue was removed using chloroform solution. To protect the MoTe$_2$ samples and ensure good optical coupling, a multilayer hBN was applied on top of the samples. Finally, a 140-nm-thick gold film was deposited on the samples for enhanced optical reflectivity during the measurements.

B. High-pressure optical measurements

The Raman spectra of the MoTe$_2$ samples were acquired using the WITec Alpha 300R system equipped with a continuous wave (cw) laser (532 nm). Raman measurements were performed using an optical grating with a line density of 1800 lines per millimeter and a 50× objective with the focal length of 3.6 mm, the work distance of 10.6 mm, and numerical aperture of 0.5. The Raman scattered light was detected by a charge-coupled device with an integration time of 5 s and accumulation of 7 at a laser power of 15 mW. The laser beam size was ∼1 μm. To generate high pressure, a DAC with a 400-μm culet size was employed. Pressure was controlled by using silicone oil as a pressure-transmitting medium, and the pressure values were calibrated using ruby granules as a pressure calibration standard [42]. By continuously adjusting the applied pressure, high-pressure Raman spectra were collected to investigate the pressure-dependent behavior of the samples.

C. Theoretical calculations

Density-functional theory (DFT) calculations were performed using the projector augmented-wave [43] method, implemented in the Vienna *Ab initio* Simulation Package (VASP) code [44]. The Perdew-Burke-Ernzerhof [45] exchange-correlation functional within the generalized gradient approximation was employed. A plane-wave energy cutoff of 520 eV and a k-point mesh of $13 \times 13 \times 1$ were used for the calculations. To avoid the interactions between periodic layers, a vacuum spacing of 20 Å was included. The crystal structure of bulk MoTe$_2$ was relaxed until the forces converged to within $0.01 \, \text{eV/Å}$ under both zero-pressure and high-pressure conditions.

III. RESULTS AND DISCUSSION

A. Low-frequency Raman spectra at ambient pressure

Bulk MoTe$_2$ crystallizes D_{6h}^4 symmetry, and has 12 irreducible representations at the Γ point [46,47]:

$$\Gamma_{\text{bulk}} = A_{1g} + 2A_{2u} + 2B_{2g} + E_{1g} + 2E_{1u} + E_{2u} + B_{1u} + 2E_{2g}, \tag{1}$$

where A_{1g}, E_{2g}^1, E_{2g}^2, and E_{1g} are Raman-active modes. As the thickness of MoTe$_2$ changes from bulk to few layers, the symmetry alters to D_{3h}^1 and D_{2d}^3 for odd- and even-number layers, respectively. Thus, the Raman-active modes become A_1', E', and E'' for odd-number layers and become A_{1g}^2, E_g^1, and E_g^2 for even-number layers corresponding to the A_{1g}, E_{2g}^1, and E_{1g} for bulk, respectively. To investigate the vibration features of MoTe$_2$ materials, the few-layer MoTe$_2$ samples were obtained by mechanically exfoliating bulk MoTe$_2$ crystals, as depicted in Fig. 1(b). Raman spectroscopy measurements were performed at room temperature and ambient pressure, as presented in Fig. 1(d). Two low-frequency modes ($< 100 \, \text{cm}^{-1}$) were observed in the Raman spectra of 2–5L MoTe$_2$ and identified as the S and LB modes. Specifically, for 2L, 3L, 4L, and 5L MoTe$_2$, the S (LB) modes were observed at 19.0 (27.0), 23.5 (19.5), 24.0 (14.5), and 25.5 cm^{-1} (11.5 cm^{-1}), respectively. The S and LB modes exhibit nonlinear blue- and redshifts, respectively, as the layer number increases, with a crossing point between 2L and 3L, which is consistent with previous findings [35].

The S and LB modes arise from the relative motion of the layers along the in-plane and out-of-plane directions, respectively, in MoTe$_2$ with N layers ($N \geqslant 2$). Each layer can be considered as a rigid atomic plane, enabling the use of the LCM [33,36,37] to describe the interlayer displacements. The vibrational frequencies of the S and LB modes can be
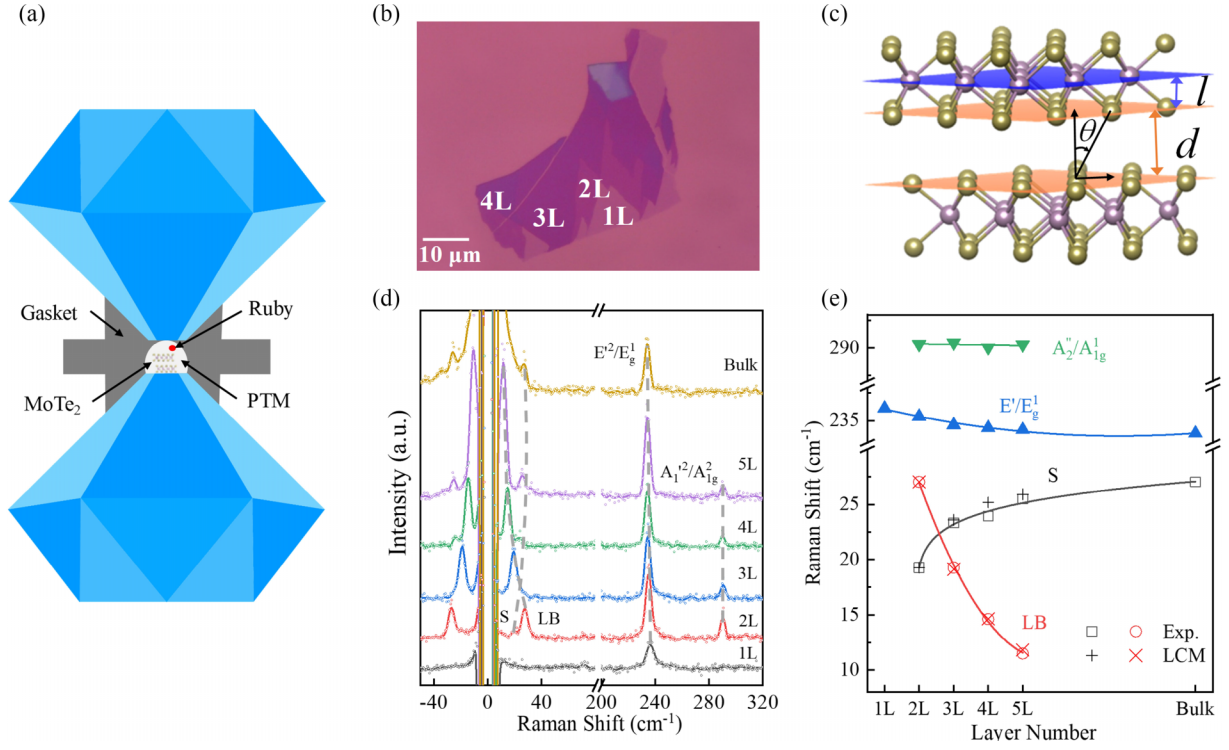
FIG. 1. Layer-dependent Raman spectra of $MoTe_2$ at ambient pressure. (a) Schematic diagram of diamond-anvil cell (DAC) device used for the experiments. (b) Optical image of few-layer $MoTe_2$ samples, including 1L, 2L, 3L, and 4L $MoTe_2$. (c) Crystal structure of $MoTe_2$, illustrating arrangement of Mo (lilac) and Te (yellowish-brown) atoms. Distances between adjacent Te atomic layers (interlayer) and between Mo and Te atomic layers (intralayer) are denoted as d and l, respectively. Angle (θ) is formed by adjacent interlayer Te–Te bonds and out-of-plane direction. (d) Raman spectra of $MoTe_2$ as function of layer number. Circle points and solid lines represent measured data and smoothing data (Loess method with window ratio of 0.008), respectively. (e) Layer-dependent Raman peak positions of $MoTe_2$. Low-frequency shear- and breathing modes exhibit blue- and redshifts, respectively, as layer number increases, consistent with results obtained from LCM.

described by the following equations:

$$\omega(S_{N,N-j}) = \frac{1}{\pi c}\sqrt{\frac{k_S}{M}}\sin\left(\frac{j\pi}{2N}\right)$$

$$\omega(LB_{N,N-j}) = \frac{1}{\pi c}\sqrt{\frac{k_{LB}}{M}}\sin\left(\frac{j\pi}{2N}\right), \quad (2)$$

where $M = m_{Mo} + 2m_{Te}$ is the total mass per unit cell, and c is the velocity of light. The j (index $j = 1, \ldots, N-1$) is equal to $N-1$ and 1 for the highest-frequency S modes and lowest-frequency LB modes, which can be observed in backscattering-configuration Raman spectra. We used the detected frequencies of S and LB modes of 2L $MoTe_2$ and the force constant of $k_S = 3.43 \times 10^{19}$ N/m³ and $k_{LB} = 6.88 \times 10^{19}$ N/m³ were obtained. The estimated results obtained from the LCM are in agreement with our measured results [see Fig. 1(e)]. Notably, these layer-dependent S and LB modes exhibit higher sensitivity to interlayer coupling compared to E'/E_g^1 and A_2''/A_{1g}^1 modes (E' and A_2'' for odd layer, while E_g^1 and A_{1g}^1 for even layer). This demonstrates the effectiveness of utilizing the interlayer S and LB modes as characterizations for studying interlayer coupling.

B. Positions of shear- and breathing modes at high pressure

To gain insight into the layer-dependent interlayer coupling in $MoTe_2$, we conducted compression experiments on

$MoTe_2$ samples with varying layer numbers (2–5L and bulk) using DAC devices. Figure 2 illustrates the low-frequency Raman spectra as a function of pressure up to approximately 14 GPa. Due to the pressure-induced phonon-hardening effect, the S and LB modes of $MoTe_2$ exhibited monotonic blueshifts within the studied pressure range. Nevertheless, the low-frequency modes displayed a nonlinear behavior, characterized by a rapid variation at low pressures and a slower increase at high pressures. This nonlinear blueshift of the S and LB modes suggests distinct variations in interlayer coupling within different pressure ranges in $MoTe_2$ materials. To comprehend this nonlinear interlayer coupling variation, we carried out structure relaxation simulations on bulk $MoTe_2$ under pressures ranging from 0 to 14 GPa using first-principle calculations. Notably, the interlayer distance (d) showed a rapid decrease at low pressures (0–2-GPa range), followed by a gradual decrease at high pressures (2–14-GPa range), which aligns with our experimental findings [see Fig. 3(d)].

Furthermore, we plotted the frequency difference ($\Delta\omega = \omega_p - \omega_0$, where ω_p and ω_0 represent frequency at high pressure and at ambient pressure, respectively) between the pressure-dependent S and LB modes and the ambient-pressure S and LB modes as a function of pressure, as shown in Figs. 3(a) and 3(b), respectively. It was observed that for the LB modes, the blueshift rates decreased as the layer number increased. In contrast, for the S modes, thicker $MoTe_2$ samples exhibited a faster blueshift rate. To quantify these
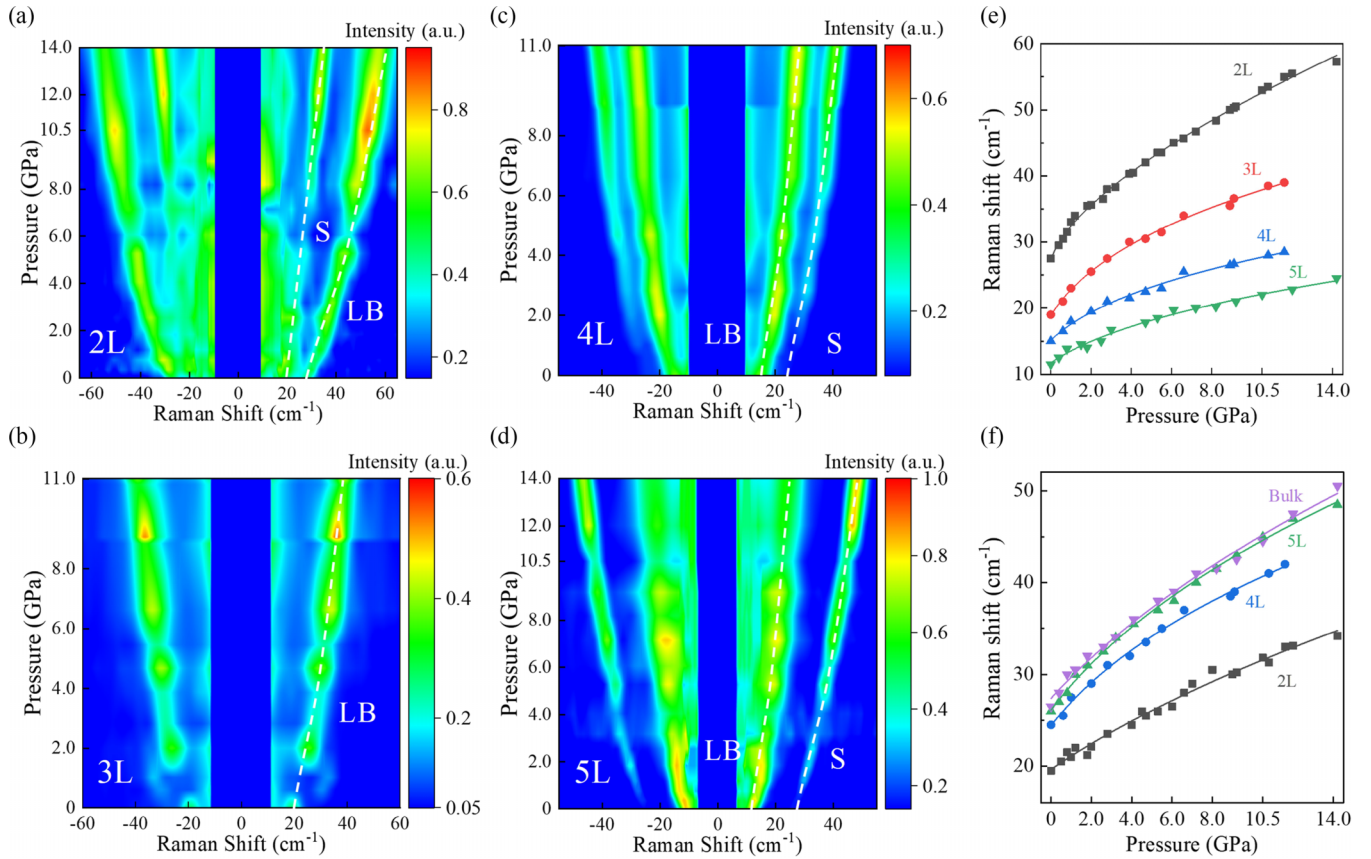
FIG. 2. Pressure-dependent low-frequency Raman spectra in layer-dependent $MoTe_2$. (a)–(c) Color plots depicting progressive changes in Raman spectra with increasing pressure for different layer thicknesses: (a) bilayer (2L) $MoTe_2$, (b) trilayer (3L) $MoTe_2$, (c) four layer (4L) $MoTe_2$, and (d) five layer (5L) $MoTe_2$. (e) Pressure-dependent variations in positions of the breathing (LB) modes. (f) Pressure-dependent variations in positions of shear (S) modes. All S and LB modes consistently exhibit blueshift as applied pressure intensifies.

observations, we fitted the measured data with a function of $\omega_N = A|p - xc|^{\alpha}$, where A and α are the amplitude and index, respectively. The fitted coefficients are listed in Table S1 of Supplemental Material (SM) [48]. Since the coefficient A predominantly controls the magnitude of the curves, we plotted the A coefficients as a function of layer number [Fig. 3(c)]. The A coefficients for the S and LB modes exhibited layer-dependent blue- and redshifts, respectively, as the layer number increased from 2L to 5L, consistent with the observed layer-dependent increase in blueshift rates for the S and LB modes under pressure. Additionally, a crossing point between the S and LB modes close to 4L suggests a small frequency difference between the S and LB modes in 4L $MoTe_2$ under pressure [Fig. 4(e)].

Simultaneously, the calculated d for 2–5L $MoTe_2$ (see Fig. 3(d) and SM Table S1 [48]) indicate an increase in interlayer coupling as the layer number increases from 2L to 5L. Thicker $MoTe_2$ samples exhibit stronger interlayer coupling, leading to a more moderate response to pressure, as observed in the pressure-dependent LB modes of $MoTe_2$ with different layer numbers. This is because structures with strong coupling exhibit greater resistance to external fields. The calculated interlayer distances, which show reduced variation rates under pressure, provide compelling evidence for the fact that strong interlayer coupling exhibits strong resistance to compression [Fig. 3(d)]. This finding also suggests that the LB modes

of $MoTe_2$ are strongly influenced by interlayer coupling. As depicted in Fig. 3(e), external pressure narrows the interlayer distance and enhances interlayer coupling. Therefore, the use of a DAC provides an effective means to tune interlayer coupling, with LB modes offering a direct means of detecting interlayer coupling.

In contrast, the entire restoring force [36] also makes a significant contribution to the S modes of $MoTe_2$, in addition to interlayer coupling. In fact, due to enhanced surface binding, the overall restoring force increases with increasing thickness, resulting in a blueshift of the S modes in Bernal-stacked graphene [36]. This trend of S-mode hardening with increasing layer number was also observed in our experimental data for $MoTe_2$ [Fig. 1(e)]. This thickness-dependent surface binding leads to an increase in the pressure-induced blueshift rate with increasing layer number. When high pressure is applied, the interlayer distance decreases, along with an increase in θ [see Fig. 4(d)], thereby enhancing interlayer coupling and surface binding. Thus, under the combined effects of enhanced interlayer coupling and overall restoring force, the S modes exhibit a pressure-induced blueshift.

Given the suitability of the rigid atomic plane assumption for NL $MoTe_2(N = 2-5)$ under pressure, we employed the pressure-dependent LCM (p-LCM) to estimate the pressure-dependent force constant and understand the variation in interlayer coupling under pressure. It should be noted that
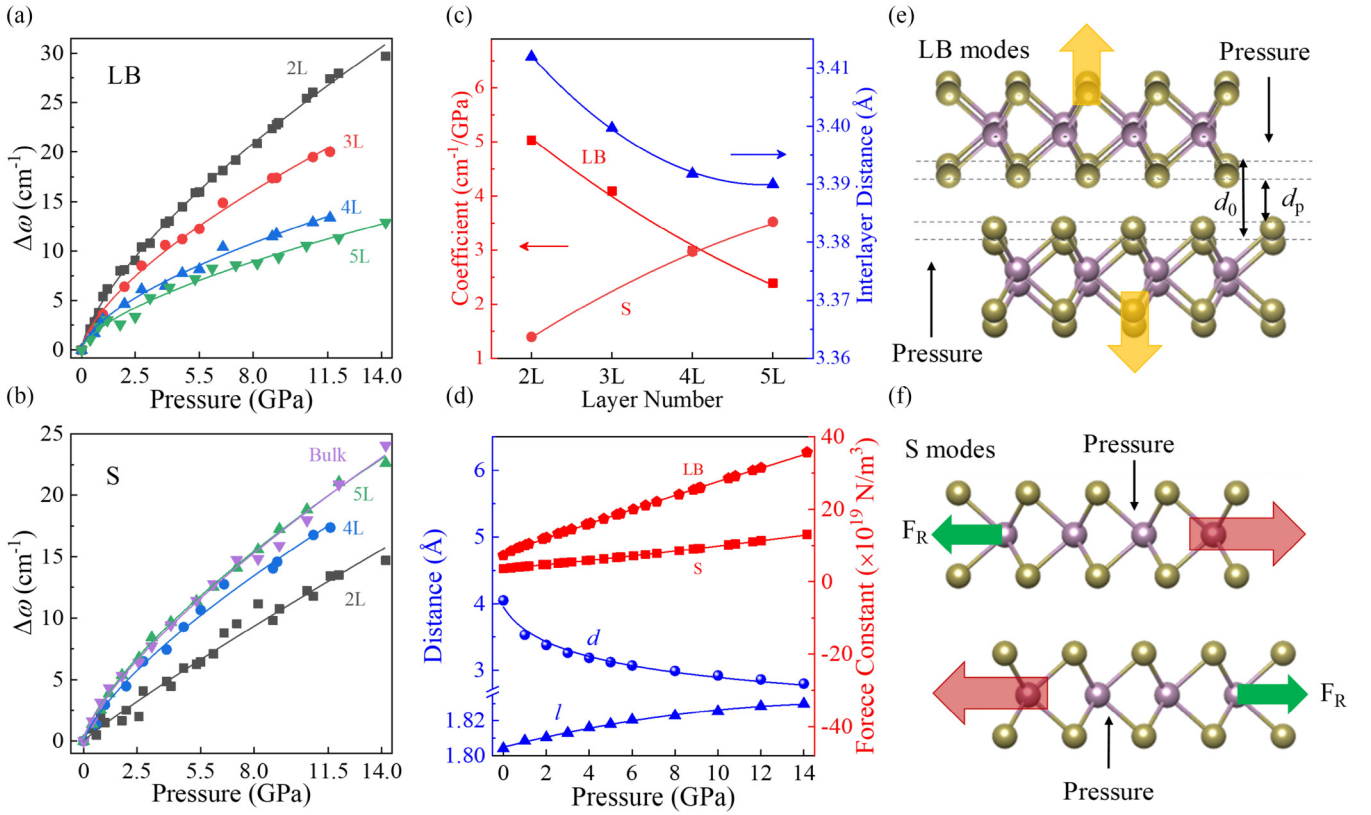
FIG. 3. Layer-dependent peak positions of S and LB modes in $MoTe_2$ under pressure. (a), (b) Normalized Raman peak positions of (a) LB and (b) S modes with different thickness as function of pressure, relative to peak position at ambient pressure. Values are denoted as $\Delta\omega = \omega_p - \omega_0$, where ω_p and ω_0 are frequencies of LB and S modes at high pressure and ambient pressure, respectively. (c) Layer-dependent calculated interlayer distance (blue line) and coefficients A for S and LB modes (red lines). (d) Pressure-dependent force constant calculated from p-LCM (red lines) and calculated interlayer (d) and intralayer (l) spacing distances of bulk $MoTe_2$ (blue lines). (e), (f) Vibration patterns of (e) LB and (f) S modes. F_R denotes restoring force.

the mass M varies with pressure due to the pressure-induced lattice reduction. The p-LCM can be expressed as follows:

$$\omega_p(S_{N,N-j,p}) = \frac{1}{\pi c}\sqrt{\frac{k_{S,p}}{M_p}}\sin\left(\frac{j\pi}{2N}\right)$$

$$\omega_p(LB_{N,N-j,p}) = \frac{1}{\pi c}\sqrt{\frac{k_{LB,p}}{M_p}}\sin\left(\frac{j\pi}{2N}\right). \quad (3)$$

Here, we adopted the calculated mass M_p of bulk $MoTe_2$ under pressure (see Fig. S3 [48]). Using our measured pressure-dependent frequencies of S and LB modes [$\omega_p(S_{2,1,p})$ and $\omega_p(LB_{2,1,p})$], we estimated the force constants $k_{S,p}$ and $k_{LB,p}$, as illustrated in Fig. 3(d). The estimated pressure-dependent LB modes for NL $MoTe_2$ ($N = 3, 4,$ and 5) closely matched the experimental data [Fig. 4(a)], confirming the feasibility of p-LCM for the LB modes of NL $MoTe_2$. Clearly, both $k_{S,p}$ and $k_{LB,p}$ exhibit a blueshift as high pressure was applied, with $k_{LB,p}$ being more sensitive to pressure than $k_{S,p}$. This implies that the strength of interlayer coupling of NL $MoTe_2$ was enhanced by high pressure, and the layer-dependent low-frequency modes at high pressure exhibited similar behavior to those at ambient pressure (i.e., pressure did not change the layer-dependent characteristic of the low-frequency Raman modes).

C. Intensity of low-frequency Raman spectra

In terms of the intensity of the S and LB modes, we observed that the intensity of the S modes was enhanced by pressure relative to the LB modes at corresponding pressures. We extracted the intensity of S and LB modes of 2L, 4L, and 5L $MoTe_2$ under pressure and plotted their ratio (I_S/I_{LB}) as a function of pressure, as shown in Fig. 4(c). It exhibits a distinct upward trend for NL $MoTe_2$ ($N = 2, 4,$ and 5), especially for 4L and 5L $MoTe_2$, which display a nearly linear increase. At approximately 10-GPa pressure, the I_S/I_{LB} ratio reaches 1 for 4L and 5L $MoTe_2$. To gain insight into the physics underlying the pressure-induced enhancement of I_S/I_{LB}, we employed the empirical bond-polarizability model [49–51]. The Raman intensity can be described according to the Placzek approximation [51,52]:

$$I(k) \propto \frac{n_k + 1}{\omega_k}\left|e_i \cdot \widetilde{R}(k) \cdot e_s^T\right|^2$$

$$= \frac{n_k + 1}{\omega_k}\left|\sum_{\mu\nu} e_{i,\mu} e_{s,\nu} \Delta\alpha_{\mu\nu}(k)\right|^2, \quad (4)$$

where $\widetilde{R}(k)$ and ω_k are the Raman tensor and frequency of phonon mode k, respectively. e_i and e_s are the polarization vector of incident and scattered light, and the μ and ν de-
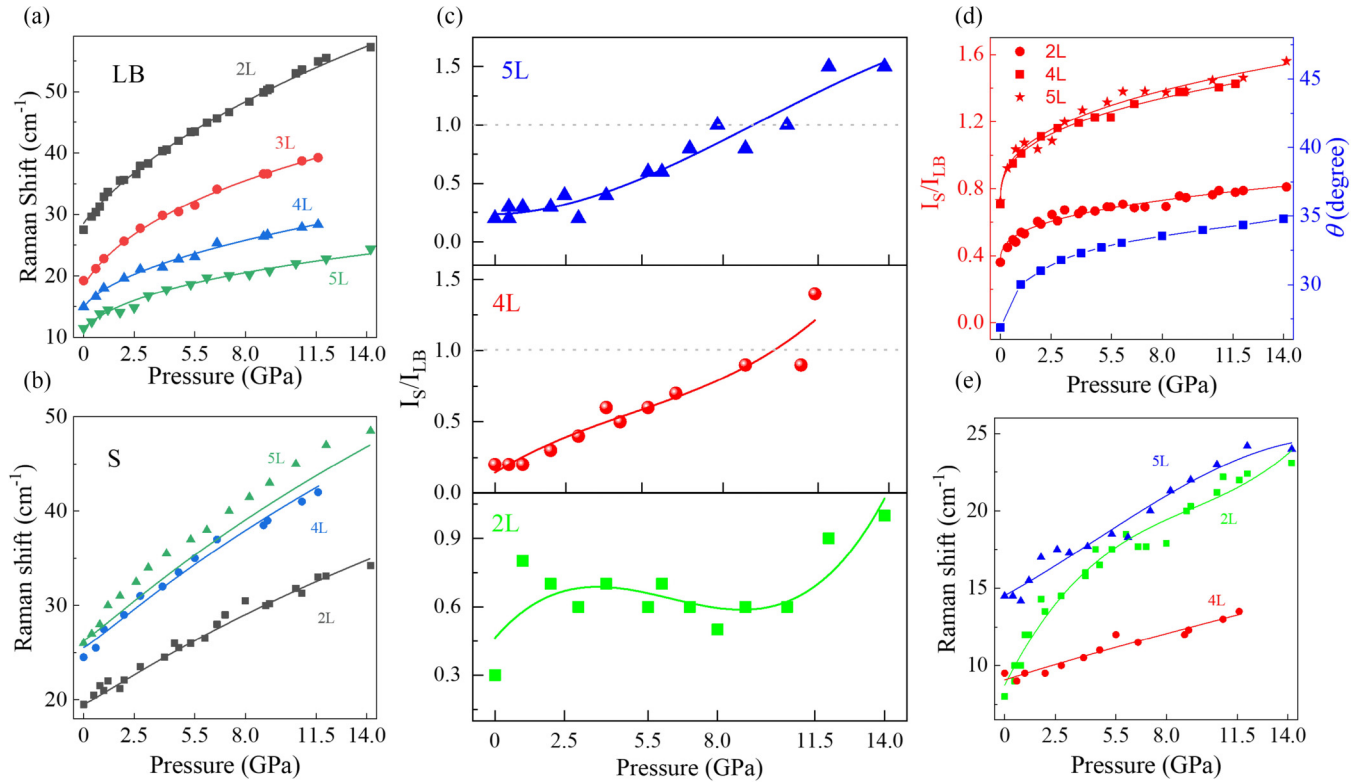
FIG. 4. Pressure-induced intensity changeover between S and LB modes of MoTe$_2$. (a), (b) Raman peak position of (a) LB and (b) S modes of few-layer MoTe$_2$. Points represent measured data, while lines denote simulated results of p-LCM. (c) Intensity ratio between S and LB modes (I_S/I_{LB}) of 2L (green), 4L (red), and 5L (blue) MoTe$_2$. Lines are provided as visual guides. (d) Calculated pressure-dependent angle (θ) by first-principle calculations (blue curves) and estimated I_S/I_{LB} of 2L, 4L, and 5L MoTe$_2$ by bond-polarization model (red curves). (e) Frequency difference between LB and S modes of 2L, 4L, and 5L MoTe$_2$ as function of pressure.

note components of the tensor, respectively. Moreover, n_k is the phonon occupancy, which can be determined using Bose-Einstein statistics [$n_k = 1/(e^{\hbar\omega_k/k_B T} - 1)$]. According to the bond-polarizability model, the Raman tensor elements $\Delta\alpha_{\mu\nu}(k)$ have the following forms [51]:

$$\Delta\alpha_{xx,\mu}(k) = \sum_i \sum_B C_{i\mu,B} \widehat{R}_{i\mu,B} \Delta r_{i\mu}. \quad (5)$$

Here, $C_{i\mu,B}$, $\widehat{R}_{i\mu,B}$, and $\Delta r_{i\mu}$ are the coefficients, normalized bond vector, and atomic displacement of μ component for bond B connected to atom i, respectively. The subscript xx represents the backscattering configuration $\widetilde{z}(xx)z$. For the S modes, the bond B has the x or y component, whereas the B is along the z component for LB modes. Therefore, the I_S/I_{LB} can be expressed as

$$\frac{I_S}{I_{LB}} \propto \frac{\omega_{LB}}{\omega_S} \left| \frac{\Delta\alpha_{xx,x}(\omega_S)}{\Delta\alpha_{xx,z}(\omega_{LB})} \right|^2. \quad (6)$$

Based on the analysis of Liang *et al.* [51] for TMDs, the Raman tensor elements are $\sqrt{2}C_{x,B}\sin\theta$, $3C_{x,B}\sin\theta$, and $\frac{8}{5}\sqrt{5}C_{x,B}\sin\theta$ [θ is the angle formed by adjacent interlayer Te–Te bond and out-of-plane direction; see Fig. 1(c)] for S modes of 2L, 4L, and 5L MoTe$_2$, respectively, while $\sqrt{2}C_{z,B}\cos\theta$ for LB modes of 2L, 4L, and 5L MoTe$_2$ within normalized layer displacements (where $C_{x,B} = C_{z,B}$). Note

that the calculated pressure-dependent θ of bulk MoTe$_2$ was adopted [Fig. 4(d)].

Figure 4(d) shows the estimated I_S/I_{LB} ratios for 2L, 4L, and 5L MoTe$_2$ using Eq. (6). These ratios increase with increasing pressure, aligning with the observed upward trend in the experimental data. This suggests that the θ, which is correlated with the interlayer distance and interlayer slipping, can affect the intensity of the S and LB modes by changing their bond polarization. As a result, pressure induces an intensity changeover between the S and LB modes in MoTe$_2$.

D. High-frequency Raman spectra

Regarding the high-frequency Raman spectra of 1L MoTe$_2$ and bulk MoTe$_2$, we observed Raman peak of $A_1'(A_{1g})$ and $E'(E_{2g}^1)$ at 171.5 (173.5) cm^{-1} and 236.0 (234.0) cm^{-1} for 1L (bulk) MoTe$_2$ at ambient pressure (see Figs. S1 and S2 of SM [48]), which are consistent with the previous results [35,46,53–55]. In NL MoTe$_2$ ($N = 2$, 3, 4, and 5), an additional infrared-active peak located around 290 cm^{-1} (A_2''/A_{1g}) [35,47] was detected at ambient pressure, as shown in Fig. 5(a) and Fig. S1 and Fig. S2 in SM [48]. All high-frequency Raman modes exhibited a monotonic blueshift under pressure. For bulk MoTe$_2$, the A_{1g} and E_{2g}^1 modes displayed different increasing tendencies in the pressure range of 0–7.0 GPa and 8.0–14.0 GPa, respectively, implying a transition from semiconductor phase to metal phase in the
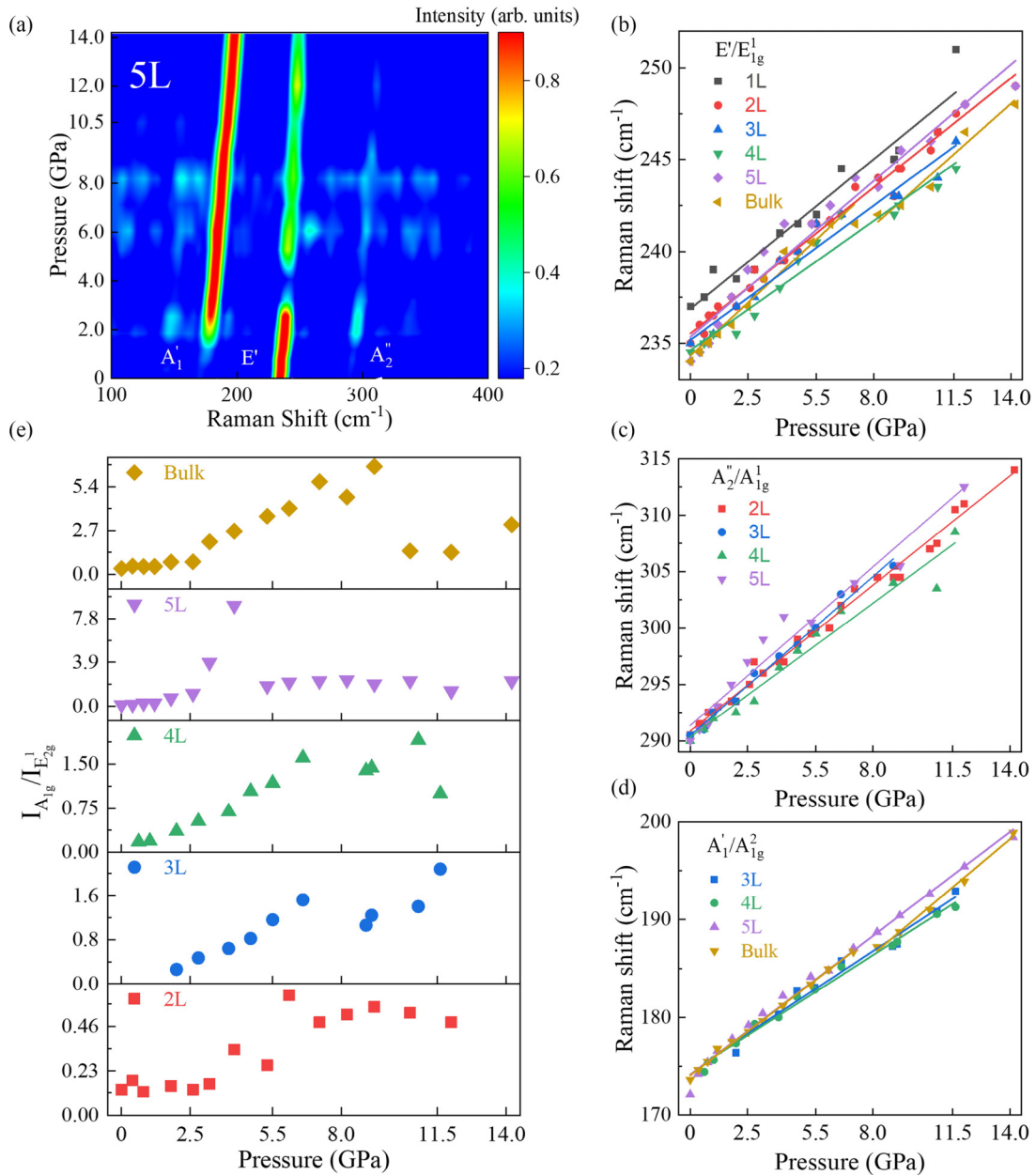
FIG. 5. High-frequency Raman spectra of MoTe$_2$ under pressure. (a) Pressure-dependent Raman spectra of 5L MoTe$_2$ in wave-number range of $100 - 400\,\mathrm{cm}^{-1}$. (b)–(d) Pressure evolution of high-frequency Raman peak positions for (b) E'/E_g^1, (c) A_2''/A_{1g}^1, and (d) A_1'/A_{1g}^2 modes. Experimental data points were extracted from Raman spectra, and solid curves represent fitted results for visual guidance. All of these vibration modes exhibit a blueshift with increasing pressure. (e) Intensity ratio between A_1'/A_{1g}^2 and E'/E_g^1 modes ($I_{A_{1g}}/I_{E_{2g}^1}$) for 2–5 L and bulk MoTe$_2$, showing an increasing trend with increasing pressure.

pressure range of 7.0–8.0 GPa. This semiconductor-to-metal transition and its transition pressure were in agreement with the previous results, with a transition pressure at around 10 GPa [55].

Moreover, the pressure-dependent high-frequency Raman positions showed little dependence on the layer number [see Figs. 5(b)–5(d)], even though the E'/E_g^1 modes decreased with increasing layer number [Fig. 1(e)]. This is in contrast to the low-frequency S and LB modes in MoTe$_2$, suggesting that intralayer vibrations are not significantly influenced by the layer number under pressure. As the stacking layers and

pressure increase, the variation in intralayer atomic vibration is small, indicating that the intralayer Te-Mo-Te configuration does not exhibit large differences between different layers due to the strong Mo–Te covalent bond, which provides significant resistance to strain.

However, their intensity can be tuned by the high pressure. We plotted the intensity ratio between A_1'/A_{1g}^2 and E'/E_g^1 modes ($I_{A_{1g}}/I_{E_{2g}^1}$) for 2–5L and bulk MoTe$_2$, as shown in Fig. 5(e). As the pressure increased, $I_{A_{1g}}/I_{E_{2g}^1}$ displayed an upward trend and showed a layer-dependent behavior (more thickness of MoTe$_2$ has higher $I_{A_{1g}}/I_{E_{2g}^1}$). To understand

the pressure-induced $I_{A_{1g}}/I_{E_{2g}^1}$ enhancement, we performed first-principle calculations of intralayer atomic and crystal relaxation for bulk $MoTe_2$ under pressure. Figure 3(d) illustrates the increasing intralayer distance between Mo and Te atomic layers (l) with increasing the pressure, resulting from enhanced Coulomb repulsion under pressure. Consequently, the increase in l leads to an increase in the out-of-plane component and a decrease in the in-plane component of Te–Mo bond. According to the bond-polarization model [Eq. (4)], the intensity of phonon vibration modes is related to the bond-polarization component. Thus, the $I_{A_{1g}}/I_{E_{2g}^1}$ can be enhanced when pressure increases the l.

Furthermore, we investigated the pressure evolution of the wave-number difference between A and E modes ($A_2'' - E'/A_{1g}^1 - E_{1g}^1$ and $E' - A_1'/E_{1g}^1 - A_{1g}^2$) in $MoTe_2$. For $A_2'' - E'/A_{1g}^1 - E_{1g}^1$, they exhibited blueshift and could be fitted with a linear trend (see Fig. S4 in SM [48]), indicating the gradual enlargement of the gaps between A_2'' and E'(or A_{1g}^1 and E_{1g}^1) for 2–5L $MoTe_2$. In contrary, the wave-number difference $E' - A_1'/E_{1g}^1 - A_{1g}^2$ declined with increasing pressure for 3–5 L and bulk $MoTe_2$, implying a crystal-structure evolution from a stratified structure to a quasi-two-dimensional or three-dimensional structure [24,32,55].

IV. CONCLUSIONS

In conclusion, our study provides a comprehensive investigation of the pressure-dependent and layer-dependent interlayer coupling and vibrational properties of NL and bulk $MoTe_2$ ($N = 1 - 5$) using DAC technology and Raman spectroscopy. Through our experimental and computational analyses, we have demonstrated that the pressure-induced blueshift rates of the low-frequency S and LB modes in $MoTe_2$ exhibit layer-dependent behavior, with the blueshift rate increasing and decreasing as the layer number increases, which arises from the layer-dependent restoring forces and interlayer coupling, respectively. Furthermore, we reveal that the intensity changeover between S and LB modes and between A_1'/A_{1g}^2 and E'/E_g^1 modes can be attributed to the pressure-induced enlarged in-plane component of interlayer Te–Te bond compared to out-of-plane component and increase of out-of-plane component of intralayer Mo–Te bond relative to in-plane component, respectively, as supported by the bond-polarization model. Our study demonstrates that $MoTe_2$ retains its layer-dependent properties even under high pressure within a homogeneous crystal structure. This layer-dependent behavior in the low-frequency interlayer vibration modes provides valuable insights into the interlayer coupling and vibrational properties of $MoTe_2$. We anticipate that

these phenomena are not exclusive to $MoTe_2$ and that the layer-dependent and pressure-dependent properties can deepen our understanding of interlayer coupling and vibrational properties for van der Waals materials [56].

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